

RoHS

compliant

6 pin TSOT23-6

IQS127 Datasheet IQ Switch[®] - ProxSenseTM Series

Single Channel Capacitive Proximity/Touch Controller

The IQS127 ProxSense[™] IC is a fully integrated capacitive sensor device produced in 2 variants:

- **IQS127D**: Dual outputs (Touch and Proximity outputs).
- **IQS127S**: Incorporating a Driven Shield.

Features

- Automatic Antenna Tuning Implementation (ATI) Automatic adjustment for optimal performance.
- Internal Capacitor Implementation (ICI) reference capacitor on-chip
- □ Supply voltage: 2V to 5.5V
- Minimum external components
- Data streaming option
- Advanced on-chip digital signal processing
- User selectable (OTP): 4 Power Modes (15uA min)
 - IO sink / source
 - Time-out for stuck key Output mode (Direct / Latch / Toggle)

		Proximity and Touch Button sensitivity
Keys:	Touch:	5mm x 5mm or larger (overlay thickness dependent)
	Proximity:	Various electrical options (wire / PCB trace / ITO / conductive foil)
Dielectric:	Material:	Various non-metal materials (i.e. glass, plastic, painted surfaces)
	Thickness:	6 mm plastic, 10 mm glass

Applications

- LCD, Plasma & LED TVs
- □ GSM cellular telephones On ear □
- detection / touch keys
- LED flashlights or headlamps
- White goods and appliances
- Office equipment, toys, sanitary ware
- Flame proof, hazardous environment Human Interface Devices
- Proximity detection enables backlighting

activation

- Wake-up from standby applications
- Replacement for electromechanical switches
- Find-In-The-Dark (FITD) applications
- Automotive: Door pocket lighting, electric window control
- GUI trigger on Proximity detected

Available options

T _A	TSOT23-6
-40°C to 85°C	IQS127D
-40°C to 85°C	IQS127S





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1 Overview

The IQS127 family is a single channel capacitive proximity and touch device which employs an internal voltage regular and reference capacitor (Cs).

The IQS127D device has a dedicated pin for the connection of a sense antenna (Cx) and output pins for proximity events on POUT and touch event on TOUT. The output pins can be configured for various output methods including a serial data streaming option on TOUT.

The IQS127S employs an active driven shield pin, which replaces the POUT pin, to drive a shield for protection of the sense antenna signal. The TOUT pin becomes a general OUT pin in the IQS127S, which is configurable either as a proximity output or a touch output.

2 Analogue Functionality

The analogue circuitry measures the capacitance of a sense antenna attached to the Cx pin through a charge transfer process (refer to section 5) that is periodically initiated by the digital circuitry. The measuring process is referred to a conversion and consists of the discharging of reference capacitor and Cx, the charging of Cx and then a series of charge transfers from Cx to Cs until a trip voltage is reached. The number of charge transfers required to reach the trip voltage is referred to as the current sample (CS).

Device configuration is determined by one time programmable (OTP) options.

The devices automatically track slow varying environmental changes via various filters, detect noise and has an automatic Antenna Tuning Implementation (ATI) to tune the device to the sense antenna.

1.1 Applicability

All specifications, except where specifically mentioned otherwise, provided by this datasheet are applicable to the following ranges:

- Temperature:-40C to +85C
- □ Supply voltage (V_{DDHI}): 2.95V to 5V
- □ Supply voltage (V_{DDHI}): 2.V to 5V Low voltage device

The capacitance measurement circuitry makes use of an internal Cs and voltage reference (V_{REF}).

The analogue circuitry further provides functionality for:

- □ Power on reset (POR) detection.
- □ Brown out detection (BOD).
- Detection of a watch dog timer (WDT) expiry.

The IQS127S employs circuitry to drive a shield that will follow the voltage sensed on Cx.





3 Packaging and Pin-out

The IQS127D and IQS127S are available in a TSOT23-6 package.

3.1 IQS127D

3.1.1 Pin-out

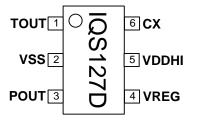




Table 3.1Pin-out description

	IQS127D					
Pin	Name	Туре	Function			
1	TOUT	Digital Out	Touch Output			
2	VSS	Ground	GND Reference			
3	POUT	Digital Out	Proximity Output			
4	VREG	Analogue Output	Internal Regulator Pin			
5	VDDHI	Supply Input	Supply Voltage Input			
6	CX	Analogue I/O	Sense Antenna			

3.1.2 Schematic

IQS127D

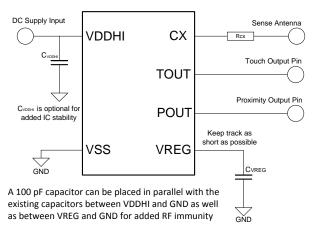


Figure 3.2 Typical application schematic of IQS127D

3.1.3 Typical values

Component	Value
C _{VREG}	1uF
R _{cx}	470 Ω (typical)
C _{VDDHI}	1uF





3.2 IQS127S 3.2.1 Pin-out

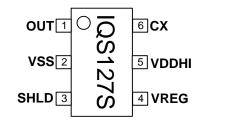


Figure 3.3 Pin-out

Pin-out of IQS127S package

Table 3.2 Pin-out description

	IQS127S					
Pin	Name	Туре	Function			
1	OUT	Digital Out	Touch or Proximity Output			
2	VSS	Ground	GND Reference			
3	SHLD	Analogue Output	Shield Output			
4	VREG	Analogue Output	Internal Regulator Pin			
5	VDDHI	Supply Input	Supply Voltage Input			
6	CX	Analogue I/O	Sense Antenna			

3.2.2 Schematic

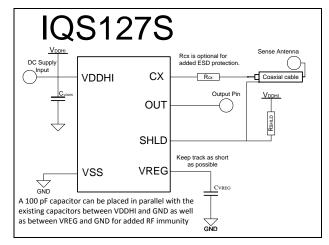


Figure 3.4 Typical application schematic of IQS127S

3.2.3 Typical values

Component	Value
C _{VREG}	1uF
R _{cx}	470 Ω (typical)
C _{VDDHI}	1uF
R _{SHLD}	2kΩ to ∞

Note: Lower values of R_{SHLD} provide a better shielding effect but require more current.





4 User Configurable Options

The IQS127 provides One Time Programmable (OTP) user options (each option can be modified only once). The device is fully functional in the default (unconfigured) state. OTP options are intended for specific applications.

The configuration of the device can be done on packaged devices or in-circuit. In-circuit configuration may be limited by values of external components chosen.

A number of standard device configurations are available (refer to Table 11.1). Azoteq can supply pre-configured devices for large quantities.

4.1 Configuring of Devices

Azoteq offers a Configuration Tool (CTxxx) and accompanying software (USBProg.exe) that can be used to program the OTP user options for prototyping purposes. More details regarding the configuration of the device with the USBProg program is explained by application note: "AZD007 – USBProg Overview" which can be found on the Azoteq website.

Alternate programming solutions of the IQS127 also exist. For further enquiries regarding this matter please contact Azoteq at ProxSenseSupport@azoteq.com or the local distributor

T _{THR1}	Т	- THR0	P _{THR1}	P _{THR0}	FUNC1	FUNC0	LOGIC	PT
bit 7								bit 0
bit 0	PT: Proximity / Touch Output (IQS127S only) 0 = Touch 1 = Proximity output			S only) -S	Section 6.1			
bit 1	LOGIC: Output logic select - 0 = Active Low			-{	Section 6.2			
bit 2-3	1 = Active High FUNC0:FUNC1 OUTPUT Pins' functions <u>IQS127D</u> 00 = POUT active, TOUT active 01 = POUT active, TOUT toggle 10 = POUT latch, TOUT active 11 = POUT latch, TOUT toggle <u>IQS127S</u> 00 = OUT active 01 = OUT latch (for t_{LATCH})			active oggle ctive	Section 6.3			
bit 4-5	Р _{ТНR0} :Р _{ТН} 00 = 2 01 = 4	10 = OL 11 = Un	JT toggle implemented, reac y Thresholds		Section 6.4			
bit 6-8	10 = 8 11 = 16	2 6 6 6 6	hresholds	-1	Section 6.5			

Table 4-1: User Selectable Configuration Options: Bank 0







Table 4-2: User Selectable Configuration Options: Bank 1

STREAMING	LTN	SHORT STREAMING	t _{HALT1}	t _{HALTO}	P _{MODE1}	P _{MODE0}	T_{THR2}
bit 15							bit 8
bit 6-8	Т_{тнк0}:Т_{тнк2}: То See Table 4-1	uch Thresholds	-	Section 6.5			
bit 9-10	PMODE0:PMODE1:Power Modes -Section 6.6 00 = Normal Power Mode -Section 6.6 01 = Low Power Mode 1 -Section 6.6 10 = Low Power Mode 2 -Section 6.6 11 = Low Power Mode 3 -Section 6.6			Section 6.6			
bit 11-12	$t_{HALT0}:t_{HATL1}:$ Halt time of Long Term Average -Section 6.7 00 = 18.6 seconds 01 = 74.5 seconds 10 = Never 11 = Always						
bit 13	SHORT STRE	AMING: Short word still led if this bit together y		3 bit is set)			
bit 14	(Function enabled if this bit together with STREAMING bit is set) LTN: Long Term Noise Filter -Section 6.7.2 0 = enabled 1 = disabled						
bit 15	STREAMING: 0 = disabled 1 = enabled	1-wire streaming debu	g mode -	Section 7			





5 Measuring capacitance using the *Charge Transfer* method

The *charge transfer* method of capacitive sensing is employed on the IQS127. (The charge transfer principle is thoroughly described in the application note: "AZD004 - Azoteq Capacitive Sensing".)

A charge cycle is used to take a measurement of the capacitance of the sense antenna (connected to Cx) relative to ground. It consists of a series of pulses charging Cx and discharging Cx to the reference capacitor, at the charge transfer frequency (F_{CX} - refer to 0). The count of the pulses required to reach a trip voltage on the reference capacitor is referred to as a sample (CS) which the current is instantaneous capacitive measurement. The CS is used to determine if either a physical contact or proximity event occurred (refer to section 6.7.1), based on the change in CS detected. The typical values of CS, without a touch or proximity condition range between 650 and 1150, although higher and lower counts can be used based on the application requirements. With CS larger than +/-1150 the gain of the system may become too high causing unsteady current samples.

The IQS127 schedules a charge cycle every t_{SAMPLE} seconds to ensure regular samples for processing of results. The duration of the charge cycle is defined as t_{CHARGE} . (refer to 0) and varies according to the counts required to reach the trip voltage. Following the charge cycle other activities such as data streaming is completed (if in streaming mode), before the next charge cycle is initiated.

Please note: Attaching a probe to the Cx pin will increase the capacitance of the sense plate and therefore CS. This may have an immediate influence on CS (decrease t_{CHARGE} – thus CS) and cause a proximity or touch event. After tHALT seconds will the system adiust to accommodate for this change. If the total load on Cx, with the probe attached is still lower than the maximum Cx load the system will continue to function normally after t_{HALT}.seconds with the probe attached.

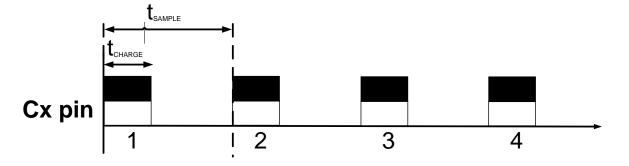


Figure 5.1 Charge cycles as can be seen on Cx

6 Descriptions of User Options

This section describes the individual user programmable options of the IQS127 in more detail.

User programmable options are programmed to One Time Programmable (OTP) fuse registers (refer to section 1). The options differ slightly between the IQS127D and IQS127S devices.

Note:

- HIGH=Logical '1' and LOW=Logical '0'.
- The following sections are explained with the OUT, POUT and TOUT taken as 'Active LOW'.
- The default is always where bits are set to 0.





Refer to section 0 for the sourcing and sinking capabilities of OUT, POUT and TOUT. These pins are sourced from V_{DDHI} and will be turned HIGH (when active high) for a minimum time of t_{HIGH} , and LOW for a minimum time of t_{LOW} (when active low).

6.1 Proximity / Touch Sensor

The IQS127S can either be configured to provide a Proximity or a Touch (default) output on the OUT pin.

The IQS127D provides a Proximity output on POUT and a Touch output on TOUT, and does not need to be configured.

Both devices will provide proximity and touch data while streaming (refer to section 7)

Configuration: Bank0 bit0

PT: Proximity / Touch Output (IQS127S only)			
Bit	Selection		
0	Touch output		
1	Proximity output		

6.2 Logic select for output(s)

The logic used by the device can be selected as active HIGH or active LOW. The output pins POUT, TOUT and OUT will function based on the selection.

6.3.1 Output Function Descriptions

6.3.1.1 Active

With a Proximity or Touch event, the output pin will change to LOW and stay LOW for as

Configuration: Bank0 bit1

LOGIC: Output logic select -Bit Selection 0 Active Low 1 Active High

6.3 Output pin function

Various options for the function of the output pin(s) are available. These are selected as follow:

Configuration: Bank0 bit2-3

FUNC0:FUNC1 OUTPUT Pins' functions					
IQS127D					
Bit	Selection				
00	POUT active, TOUT active				
01	POUT active, TOUT toggle				
10	POUT latch, TOUT active				
11	POUT latch, TOUT toggle				
<u>IQS12</u>	<u>27S</u>				
Bit	Selection				
00	OUT active				
01	OUT latch (for t _{LATCH})				
10	OUT toggle				

11 Unimplemented, read as '00'

long as the event remains (see Figure 6.1). Also refer to the use of t_{HALT} section 6.7.1 that may cause the termination of the event.

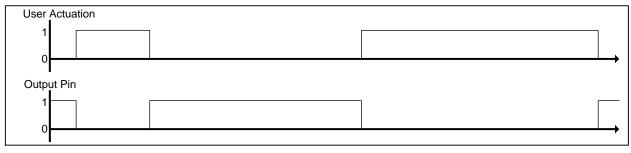


Figure 6.1 Active Mode Output Configuration

6.3.1.2 Latch (for t_{LATCH})

With a Proximity or Touch event, the output pin will latch LOW for t_{LATCH} seconds.

When the event terminates prior to t_{LATCH} the output pin will remain LOW.

When the event remains active longer than t_{LATCH} the output pin will remain LOW as long as the event remains active (see Figure 6.2).





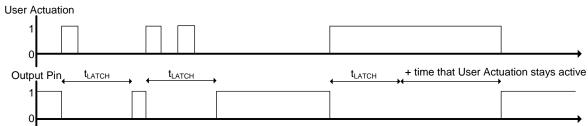


Figure 6.2 La

Latch Mode Output Configuration

6.3.1.3 **Toggle**

The output pin will toggle with every Proximity or Touch event occurring. Thus when an event

occurs and the output is LOW the output will become HIGH and when the output is HIGH the output will become LOW (see Figure 6.3).

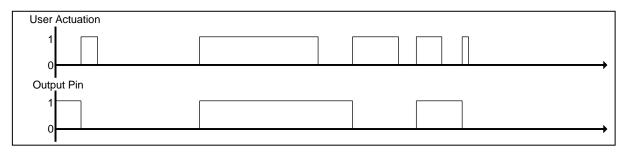


Figure 6.3 Toggle Mode Output Configuration

6.4 **Proximity Threshold**

The IQS127 has 4 proximity threshold settings. The proximity threshold is selected by the designer to obtain the desired sensitivity and noise immunity. The proximity event is triggered based on the selected proximity threshold; the CS, LTA (Long Term Average) and LTN (Long Term Noise) filter. The threshold is expressed in terms of counts; the same as CS (refer to 5)

Configuration: Bank0 bit4-5

P _{THR0}	PTHR0:PTHR1: Proximity Thresholds			
Bit	Selection			
00	2 (Most sensitive)			
01	4			
10	8			
11	16 (Least sensitive)			

The selected Proximity Threshold (P_{TH}) is used to calculate a dynamic proximity threshold (D_{TH}) as follows:

$D_{TH} = P_{TH} + 2 \times LTN$

Where LTN is the Long Term Noise value (refer to $6.7.2)\,$

A proximity event is identified when for at least 4 consecutive samples the following equation holds:

$D_{TH} = < LTA-CS$

Where LTA is the Long Term Average (refer to 6.7.1)

6.5 Touch Threshold

The IQS127 has 8 touch threshold settings. The touch threshold is selected by the designer to obtain the desired touch sensitivity. The touch threshold is expressed as a fraction of the LTA as follows:

 T_{TH} = Selected Touch Threshold x LTA

Where LTA is the Long Term Average (refer to 6.7.1)

The touch event is triggered based on T_{TH} , CS and LTA. A touch event is identified when for at least 4 consecutive samples the following equation holds:

With lower average CS (therefore lower LTA) values the touch threshold will be lower and visa versa.





Configuration: Bank0 bit6-7 and Bank1 bit1

T _{THR0} :	T _{THR2} : Touch Thresholds
Bit	Selection
000	1/16
001	1/32 (Most sensitive)
010	2/16
011	3/16
100	4/16
101	6/16
110	8/16
111	10/16 (Least sensitive)

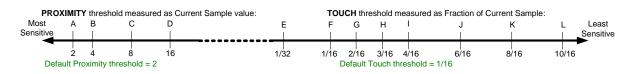


Figure 6.4Proximity and Touch Thresholds

6.6 **Power Modes**

The IQS127 IC has four power modes specifically designed to reduce current consumption for battery applications.

The power modes are basically implemented around the occurrence of charge cycle every t_{SAMPLE} seconds (refer to section 5). The fewer charge transfer cycles that need to occur per second the lower the power consumption (but increased response time).

During normal operation charge cycles are initiated approximately every 9ms. This is referred to as Normal Power Mode (NP).

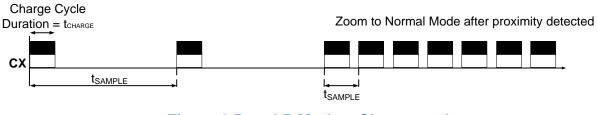
Three Low Power Modes are provided. While in any power mode the device will zoom to NP whenever a current sample (CS) indicates a possible proximity or touch event. The device will remain in NP for t_{ZOOM} seconds and then return to the selected power mode. The Zoom function allows reliable detection of events with current samples being produced at the NP rate.

Table 6-1: Power Mode timings

Power Mode timing	t _{SAMPLE} (ms)
t _{NP} (default)	NP (9ms)
t _{LP1}	50
t _{LP2}	100
t _{LP3}	200

Configuration: Bank1 bit2-3

PMODE0:PMODE1:Power Modes				
Bit Selection				
00	Normal Power Mode (NP)	-t _{NP,}	9.1	
01	Low Power Mode 1 (LP1)	-t _{LP1}	50	
10	Low Power Mode 2 (LP2)	-t _{LP2}	100	
11	Low Power Mode 3 (LP3)	-t _{LP3}	200	









6.7 Filters used by the IQS127

The IQS127 devices employ various signal processing functions that includes the execution of various filters as described below.

6.7.1 Long Term Average (LTA)

Capacitive touch devices detect changes in capacitance that are not always related to the intended proximity or touch of a human. This is a result of changes in the environment of the sense plate and other factors. These changes need to be compensated for in various manners in order to reliably detect touch events and especially to detect proximity events. One mechanism the IQS127 employs is the use of a Long Term Averaging filter (IIR type filter) which tracks slow changes in the environment (expressed as changes in the current sample). The result of this filter is a Long Term Average (LTA) value that forms a dynamic reference used for various functions such as identification of proximity and touch events.

The LTA is calculated from the current samples (CS). The filter only executes while no proximity or touch event is detected to ensure compensation only for environmental changes. However there may be instances where sudden changes in the environment or changes in the environment while a proximity or touch event has been detected cause the CS to drift away from the LTA. To compensate for these situations a Halt Timer (t_{HALT}) has been defined.

The Halt Timer is started when a proximity or touch event occurs and when it expires the LTA filter is recalibrated. Recalibration causes LTA < CS, thus the disappearance of proximity or touch events (refer to 6.4 and 6.5).

The designer needs to select a Halt Timer value to best accommodate the required application.

Configuration: Bank1 bit4-5

t _{HALT0} :	t _{HATL1} : Halt time of Long Term Average
Bit	Selection

- 00 18.6 seconds
- 01 74.5 seconds
- 10 NEVER
- 11 ALWAYS

Notes:

- The "NEVER" option indicates that the execution of the filters will never be halted.
- With the 'ALWAYS' option and the detection of a <u>proximity</u> event the execution of the filter will be halted for only 18.6 seconds and with the detection of a <u>touch</u> event the execution of the filter will be halted as long as the touch condition applies.

Refer to Application note "AZD024 -Graphical Representation of the IIR Filter" for detail regarding the execution of the LTA filter.

6.7.2 Long Term Noise (LTN) Filter

The IQS127 implements a dynamic Long Term Noise filter, tracking noise in the current samples as a LTN value. The LTN value is used to adjust the dynamic threshold used to determine proximity events (refer to 6.4). The LTN value enables the device to withstand false detections caused by noise coupling in from constant noise sources. The execution of the LTN filter can be disabled which will cause the LTN value to be set to 0. The LTN value is limited to <= 8.

Configuration: Bank1 bit7

LTN: Long Term Noise Filter execution				
Bit	Selection			
0	Enabled			

1 Disabled

6.7.3 IIR Raw Data filter

The extreme sensitivity of the IQS127 makes it susceptible to external noise sources. This causes a decreased signal to noise (S/N) ratio, which could potentially cause false event detections.

Noise can also couple into the device as a result of poor PCB, sense antenna design





and other factors influencing capacitive sensing devices.

In order to compensate for noise the IQS127 uses an IIR filter on the raw data to minimize

7 Data Streaming Mode

The IQS127 has the capability to stream data to a MCU. This provides the designer with the capability to obtain the parameters within the device in order to aid design into applications. Data streaming may further be used by an MCU to control events or further process results obtained from the IQS127 devices. Data streaming is performed as a 1-wire data protocol on one of the output pins (TOUT for IQS127D devices and OUT for IQS127S devices). The function of this pin is therefore lost when the device is put in streaming mode. Data Streaming can be enabled as indicated below:

Configuration: Bank1 bit8

STREAMING: 1-wire data streaming mode			
Bit	Bit Selection		
0	Disabled		
1	Enabled		

The IQS127D has a short data streaming mode where a reduced set of data is streamed to the MCU. This option can be used only when data streaming has been activated.

result of noise in the current sample. This filter is implemented on all of the IQS127 devices, and cannot be disabled.

Configuration: Bank1 bit6

SHORT STREAMING: Short data streaming			
Bit	Selection		
0	Disabled		
1	Enabled		

Data streaming is initiated by the IQS127. When data streaming is enabled data is sent following each charge cycle (refer to 5).

Figure 7.1 illustrates the communication protocol for initialising and sending data with the 1 wire communication protocol.

- 1. Communications is initiated by a START bit. This bit is defined as a low condition for t_{START} .
- 2. Following the START bit a synchronisation byte ($T_{INIT} = 0xAA$) is sent. This byte is used by the MCU for clock synchronisation.
- Following T_{INIT} the data bytes will be sent. With short data streaming mode enabled, 5 bytes of data will be sent, else 8 bytes will be sent after each charge cycle.
- 4. Each byte sent will be proceeded by a START bit and a STOP bit will follow every byte.
- A STOP bit is indicated by taking pin 1 high. The STOP bit does not have a defined period.

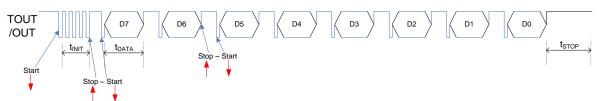


Figure 7.1

Debug: 1-wire streaming Debug Mode

The following tables define the data streamed from the IQS127 devices during and Short Data Streaming and Normal Data Streaming modes.





Table 7.1Byte Definitions for ShortData Streaming Mode

Byte	Bit	Value				
0	7:0	Current sample High byte				
1	15:8	Current sample Low byte				
4	23	Proximity event detected				
	22	Touch event detected				
	21	Not used (always 0)				
	20	Zoom active				
	19	LTN value (b3)				
	18	LTN value (b2)				
	17	LTN value (b1)				
	16	LTN value (b0)				

Table 7.2Byte Definitions for NormalData Streaming Mode

Byte	Bit	Value
0	7:0	CS High byte
1	15:8	CS Low byte
2	23:16	LTA High byte
3	31:24	LTA Low byte
4	39	ATI busy
	38	Compensation (P5)
	37	P _{TH0} – Proximity threshold
	36	P _{TH1} – Proximity threshold
	35	Not used (always 0)
	34	Zoom active
	33	Touch event detected
	32	Proximity event detected
5	47	ATI Multiplier (I)
	46	ATI Multiplier (S)
	45	ATI Multiplier (S)
	44	Compensation (P4)
	43	Compensation (P3)
	42	Compensation (P2)
	41	Compensation (P1)
	40	Compensation (P0)
6	55:48	Long Term Noise value
7	63:56	Counter

Azoteq provides an application tool: "VisualProxSense" that can be utilised to capture and visualise the data streamed from the IQS127 (refer to application note AZD006 - VisualProxSense_Overview).

Long debug mode used when all data is required from IC. Short debug mode used when only instantaneous measurement and Prox/Touch event is needed.

Sample code available: "AZD017 - IQS127 1-Wire Protocol SAMPLE CODE"

8 Antenna Tuning Implementation (ATI)

ATI is a sophisticated technology implemented in the latest generation $ProxSense^{TM}$ devices that optimises the performance of the sensor in a wide range of applications and environmental conditions (refer to application note AZD0027 - Antenna Tuning Implementation).

ATI makes adjustments through external reference capacitors (as required by most

other solutions) to obtain optimum performance.

ATI adjusts internal circuitry according to two parameters, the ATI multiplier and the ATI compensation. The ATI multiplier can be viewed as a course adjustment and the ATI compensation as a fine adjustment.





The adjustment of the ATI parameters will result in variations in the current sample and sensitivity. Sensitivity can be observed as the change in current sample as the result of a <u>fixed</u> change in sensed capacitance. The ATI parameters have been chosen to provide significant overlap. It may therefore be possible to select various combinations of ATI multiplier and ATI compensation settings to obtain the same current sample. The sensitivity of the various options may however be different for the same current sample.

8.1 Automatic ATI

The IQS127 implements an automatic ATI algorithm. This algorithm automatically adjusts the ATI parameters to optimise the sensing antenna's connection to the device.

The device will execute the ATI algorithm whenever the device strarts-up and when the current samples are not within a predetermined range.

While the Automatic ATI algorithm is in progress this condition will be indicated in the streaming data and proximity and touch events cannot be detected. The device will only briefly remain in this condition and it will be entered only when relatively large shifts in the current sample has been detected.

The automatic ATI function aims to maintain a constant current sample, regardless of the capacitance of the sense antenna (within the maximum range of the device).

The effects of auto-ATI on the application are the following:

Automatic adjustment of the device

configuration and processing parameters for a wide range of PCB and application designs to maintain a optimal configuration for proximity and touch detection.

- Automatic tuning of the sense antenna at start-up to optimise the sensitivity of the application.
- Automatic re-tuning when the device detects changes in the sensing antenna's capacitance to accommodate a large range of changes in the environment of the application that influences the sensing antenna.
- Re-tuning only occurs during device operation when a relatively large sensitivity reduction is detected. This is to ensure smooth operation of the device during operation.
- Re-tuning may temporarily influences the normal functioning of the device, but in most instances the effect will be hardly noticeable.
- Shortly after the completion of the retuning process the sensitivity of a Proximity detection may be reduced slightly for a few seconds as internal filters stabilises.

Automatic ATI can be implemented so effectively due to:

- Excellent system signal to noise ratio (SNR).
- Effective digital signal processing to remove AC and other noise.
- The very stable core of the devices.
- The built in capability to accommodate a large range of sensing antenna capacitances.





9 IQS127 Noise Immunity

The IQS127 has advanced immunity to RF noise sources such as GSM cellular telephones, DECT, Bluetooth and WIFI devices. Design guidelines should however be followed to ensure the best noise immunity. The design of capacitive sensing applications can encompass a large range of situations but as a summary the following should be noted to improve a design:

- A ground plane should be placed under the IC, except under the Cx line.
- All the tracks on the PCB must be kept as short as possible.
- A 100 pF capacitor can be placed in parallel with the 1uF capacitor between V_{DDHI} and V_{SS} . Another 100 pF capacitor can be placed in parallel with the 1uF capacitor between V_{REF} and V_{SS} .

- When the device is too sensitive for a specific application a parasitic capacitor (max 5pF) can be added between the Cx line and ground.
- Proper sense antenna and button design principles must be followed.
- Unintentional coupling of sense antenna to ground and other circuitry must be limited by increasing the distance to these sources or making use of the driven shield.
- In some instances a ground plane some distance from the device and sense antenna may provide significant shielding from undesired interference.
- When then the capacitance between the sense antenna and ground becomes too large the sensitivity of the device may be influenced.





10 Electrical Specifications

10.1 Absolute Maximum Specifications

Exceeding these maximum specifications may cause damage to the device.

Operating temperature	-40°C to 85°C
Supply Voltage (V _{DDHI} – V _{SS})	5.5V
Maximum pin voltage (OUT, T _{OUT} , P _{OUT})	V_{DDHI} + 0.5V
Pin voltage (Cx)	2.5V
Minimum pin voltage (VDDHI, VREG, OUT, T _{OUT} , P _{OUT} , Cx)	V _{SS} - 0.5V
Minimum power-on slope	100V/s
ESD protection ¹ (VDDHI, VREG, V _{SS} , T _{OUT} /OUT, P _{OUT} /SHLD, Cx)	2kV

10.2 General Characteristics (Measured at 25°C)

Standard IQS127 devices are rated for supply voltages between 2.95V and 5V. The low voltage version of the IQS127 is rated for supply voltages between 2.0V and 5V. For supply voltages below 2.95V the device is operating below the voltage required by the internal regulator and some of the characteristics of the device may be different than those for the Standard IQS127. This low voltage device is only available for the IQS127D.

DESCRIPTION	IC	Conditions	PARAMETER	MIN	TYP	MAX	UNIT
Supply voltage ²	D		V _{DDHI}	2.95		5.50	V
Internal regulator output	D	$2.95 \le V_{DDHI} \le 5.0$	V _{REG}	2.35	2.50	2.65	V
Internal regulator output ³	D	$2.0 \le V_{DDHI} \le 2.95$	V _{REG}	1.80	V_{DDHI}	V_{DDHI}	V
Normal operating current	D	V _{DDHI} =3V	I _{IQS127D_NP}	75			μA
Low power operating current	D	V _{DDHI} =3V	I _{IQS127 D_LP3}	15			μA
Normal operating current	D	V _{DDHI} =2V	I _{IQS127R/D_NP}	60			μA
Low power operating current	D	V _{DDHI} =2V	I _{IQS127 R/D_LP3}	11			μA

Table 10.1 IQS127D General Operating Conditions

Table 10.2 IQS127S General Operating Conditions

DESCRIPTION	IC	Conditions	PARAMETER	MIN	TYP	MAX	UNIT
Supply voltage	S		V _{DDHI}	4.50		5.50	V
Normal operating current	S	V _{DDHI} =4.50V	I _{IQS127S_NP}	125			μA
Low power operating current	S	V _{DDHI} =4.50V	I _{IQS127S_LP3}	75			μA

¹ See Section 10.4 for futher details

² Applicable to standard version IQS127D

³ Low voltage version of IQS127D





Table 10.3 Start-up and shut-down slope Characteristics

DESCRIPTION	IC	Conditions	PARAMETER	MIN	MAX	UNIT
POR	D/S	V _{DDHI} Slope ≥ 100V/s	POR	1.45	1.70	V
BOD	D/S		BOD	1.30	1.40	V

10.3 Output Characteristics (Measured at 25°C)

Table 10.4 OUT and TOUT Characteristics

Symbol	Description	I _{SOURCE} (mA)	Conditions	MIN	TYP	MAX	UNIT
	Output High voltage	1	$V_{DDHI} = 5V$		4.5		
V _{OH}		1	$V_{DDHI} = 3.3V$		2.97		V
		1	$V_{DDHI} = 2.5V$		2.25		
Symbol	Description	I _{SINK} (mA)	Conditions	MIN	TYP	MAX	UNIT
	Output Low voltage	1	$V_{DDHI} = 5V$	0.30	0.50		
V _{OL}		1	$V_{DDHI} = 3.3V$	0.20	0.33		V
		1	$V_{DDHI} = 2.5V$	0.20	0.25		

Table 10.5POUT Characteristics

Symbol	Description	I _{SOURCE} (mA)	Conditions	MIN	TYP	MAX	UNIT
	Output High voltage	5.0	$V_{DDHI} = 5V$		4.5		
V _{OH}		2.5	$V_{DDHI} = 3.3V$		2.97		V
		2.5	$V_{DDHI} = 2.5V$		2.25		
Symbol	Description	I _{SINK} (mA)	Conditions	MIN	TYP	MAX	UNIT
		3.0	$V_{DDHI} = 5V$	0.1	0.5		
V _{OL}		2.5	$V_{DDHI} = 3.3V$	0.1	0.33		V
		2.5	$V_{DDHI} = 2.5V$	0.1	0.25		





10.4 Electromagnetic Compatibility

EMC tests conducted and classified with the following classes:

Table 10.6 Operational level after/during test

Class	Condition
А	Module to operate as intended during test. No degradation of performance or loss of function is allowed below a performance level specified. (Only applicable to IEC61000-4-3 and IEC61000-4-6)
В	The module shall continue to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified. During the test, degradation of performance is however allowed. No change of actual operating state is allowed
С	A temporary loss of function is allowed, provided the function is self recoverable or can be restored by operating the controls or by any operation specified in the instructions for use.
D	A complete malfunction and even a destruction of the electronic control is allowed but the apparatus shall not become unsafe.

10.4.1 Electrostatic discharge (ESD)

Table 10.7 ESD Characteristics

Symbol	Ratings	Conditions	Level/ Class	Maximum Value	UNIT
$V_{\text{ESD(HBM)}}$	Electrostatic discharge voltage (Human body model)	$T_A = +25$ °C, conforming to JESD22-A114	2	2000	V
V _{ESD(CDM)}	Electrostatic discharge voltage (Charge device model)	$T_A = +25^{\circ}C$, conforming to JESD22-C101-D	IV	1000	V
V _{ESD(Product)}	Electrostatic discharge voltage (Product specification) ⁴	$T_A = +25^{\circ}C,$ conforming to IEC61000-4-2, Air- discharge on Cx, SHLD	4/	±8	kv
V _{ESD(Product)}	Electrostatic discharge voltage (Product specification) ⁴	$T_A = +25^{\circ}C,$ conforming to IEC61000-4-2, Contact-discharge on Cx, SHLD	1	±1	kv
V _{ESD} (Product)	Electrostatic discharge voltage (Product specification) ⁴	$T_A = +25^{\circ}C,$ conforming to IEC61000-4-2, Contact-discharge on V_{DDHI}, V_{SS}	3	±6	kv

⁴ Product specification is dependent on PCB layout





10.4.2 EMI (Radio frequency Interference) – IEC61000-4-3

Table 10.8 EMI (Radio frequency Interference) – IEC61000-4-3

Monitored frequency band (Mhz)	Immunity level (V/m)	Level/Class	Conditions		
80-270	3	2/A			
270-1000	10	3/A			
850-1000	30	4/A	V _{DDHI} = 5V, T _A = +25°C, TSOT23-6		
1800-1900	30	4/A	130123-0		
2300-2500	30	4/A			

10.4.3 Fast Transient Bursts – IEC61000-4-4

Table 10.9 Fast Transient Bursts – IEC61000-4-4

Level/Class	Parameter	Conditions
4/C	Fast transient voltage burst limits to be applied through 100pF on V_{DDHI} and V_{SS} pins to induce a functional disturbance	$V_{DDHI} = 5V, T_A = +25^{\circ}C,$ TSOT23-6

10.4.4 Surge – IEC61000-4-5

Table 10.10 Surge – IEC61000-4-5

Level/Class	Parameter	Conditions
4/A	Surge conducted on L->L, L->N, L->PE, N->PE, 5 each	$V_{DDHI} = 5V, T_A = +25^{\circ}C,$ TSOT23-6

10.4.5 Injected Current – IEC61000-4-6

Table 10.11 Injected Current – IEC61000-4-6

Level/Class	Parameter	Conditions
3/C	150kHz-80MHz conducted disturbances on all pins	$V_{DDHI} = 5V, T_A = +25^{\circ}C,$ TSOT23-6

10.4.6 Static Latch-Up (LU)

Table 10.12 Static Latch-Up (LU)

Symbol	Ratings	ings Conditions			
LU	Static latch-up class	$T_A = +25^{\circ}$ C, conforming to EIA/JESD 78 IC latch-up standard	А		

For detailed test results please send request to Azoteq.





10.5 Timing Characteristics

Table 10.13 Main Oscillator NP mode⁵

SYMBOL	DESCRIPTION	Conditions	MIN	TYP	MAX	UNIT
F _{OSC}	IQS127D Main oscillator	$2.95 \le V_{DDHI} \le 5.0$	0.9	1	1.1	MHz
Fosc	IQS127S Main oscillator	$4.5 \le V_{DDHI} \le 5.0$	0.9	1	1.1	MHz
F _{OSC}	IQS127D Main oscillator	$2.0 \le V_{DDHI} \le 2.95$	0.9	1.1	1.3	MHz

Table 10.14 General Timing Characteristics for $2.95V \le V_{DDHI} \le 5.0V$

SYMBOL	DESCRIPTION	Conditions	MIN	ТҮР	MAX	UNIT
t _{HIGH}	Output high minimum time		9			ms
t _{LOW}	Output low minimum time		9			ms
F _{CX}	Charge transfer frequency			125		kHz
t _{LATCH}	OUT high time in latch mode (active high)			4.6		sec
t _{CHARGE}	Charge cycle duration	CS = 900		7.2		ms
t _{SAMPLE}	Refer to section 5					ms
t _{NP}	Sampling period in NP	t _{CHARGE} - 2 ≤ t _{SAMPLE}		9		ms
t _{NP}	Sampling period in NP	t _{CHARGE} ≥ t _{SAMPLE}		t _{CHARGE} +2		ms
t _{start}	Refer to section 7		14.4	17	18.8	us
t _{INIT}	Refer to section 7			136		us
t _{DATA}	Refer to section 7			136		us
t _{LP1}	Sampling period in LP1			50		ms
t _{LP2}	Sampling period in LP2			100		ms
t _{LP3}	Sampling period in LP3			200		ms
t _{zоом}	Period in NP after possible event			4.6		S

Table 10.15 IQS127 Response Times

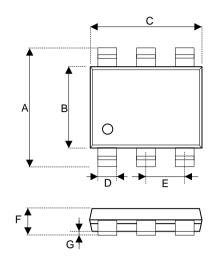
Power Mode	Proximity			
Fower mode	Min	Max	Unit	
Normal Power	54	63	ms	
Low Power 1	95	145	ms	
Low Power 2	145	245	ms	
Low Power 3	245	445	ms	
Power Mode	Touch			
Fower Mode	Typical		Unit	
All	250		ms	

⁵ All timings are derived from the main oscillator.





10.6 Packaging Information



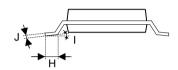


Figure 10.1

TSOT23-6 Packaging⁶

Table 10.16 TSOT23-6 Dimensions

Dimension	Min	Max	Tolerance
A	2.80 mm typ		Basic
В	1.60 mm typ		Basic
С	2.90 mm typ		Basic
D	0.40 mm		±0.10mm
E	0.95 mm typ		Basic
F	1.00mm		Max
G	0.05 mm		±0.05mm
Н	0.40 mm		±0.10mm
1	4°		±4°
J	0.127 mm typ		+0.07/-0.007

⁶ Drawing not on Scale





11 Datasheet and Part-number Information

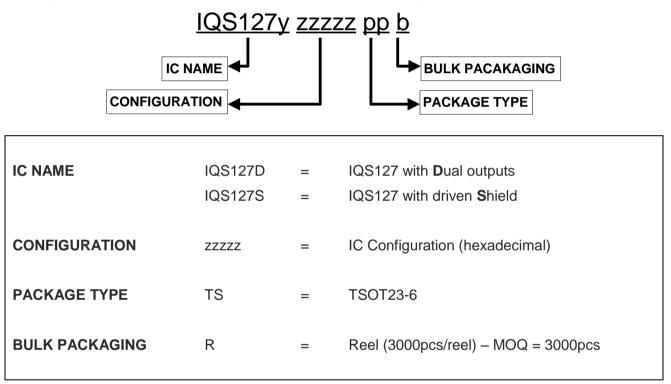
11.1 Ordering Information

Orders will be subject to a MOQ (Minimum Order Quantity) of a full reel. Contact the official distributor for sample quantities. A list of the distributors can be found under the "Distributors" section of <u>www.azoteq.com</u>.

For large orders, Azoteq can provide pre-configured devices.

The Part-number can be generated by using USBProg.exe or the Interactive Part Number generator on the website.

Standard IQS127 devices are rated for 2.95V <= V_{DDHI} <= 5V. The low voltage version of the IQS127D devices (2.0V <= V_{DDHI} <= 5V) must be specifically ordered. Please contact Azoteq directly for these orders, as it will have a different MOQ and price from the standard ICs.



11.2 Standard Devices

The default (unconfigured) device will be suitable for most applications. Some popular configurations are kept in stock and do not require further programming. (Ordering codes given for Device IDs: 03 0D / 03 0E or later (the Device ID will be read in USBProg))



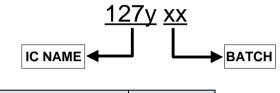


Table 11.1 Standard Devices Available

Standard Devices ⁷	Function
IQS127S-00000TSR	Default
IQS127D-00000TSR	Default
IQS127D-00002TSR	Active HIGH outputs
IQS127D-00008TSR	Touch = toggle output mode (Light Switch mode)
IQS127D-00200TSR	Low Power Mode 1

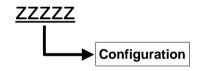
11.3 Device Packaging Convention

11.3.1 Top



BATCH	XX	
IC Name	127S	
	127D	

11.3.2 Bottom



11.4 Datasheet Revision History

- Version 1.0 First official release
- Version 1.1 Add BOD and POR

Correct formatting errors

Correct minor errors

Version 1.2 – Edited version (Final Production release)

⁷ All configurations 'default' except those mentioned under Function





12 Contact Information

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Numerous patents relate to the device, the usage of the device and the user interface. Please contact Azoteq for any IP related matters.

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